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|-----------------------------------|--|-------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/577,815 | SCHERBLE ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |
| | | Jeffrey Lenihan | 1796 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|--|-----------------|----------------------|----------------|
| * | A | US-4,847,908 A | 07-1989 | Nieuwendijk et al. | 381/424 |
| * | B | US-5,225,449 A | 07-1993 | Tada et al. | 521/77 |
| * | C | US-5,928,459 A | 07-1999 | Geyer et al. | 156/331.1 |
| * | D | US-2002/0037955 A1 | 03-2002 | Baumann et al. | 524/495 |
| * | E | US-6,396,451 B1 | 05-2002 | Wu et al. | 343/756 |
| * | F | US-2004/0034932 A1 | 02-2004 | Zacharopoulos et al. | 5/601 |
| * | G | US-2004/0235973 A1 | 11-2004 | Stein et al. | 521/189 |
| H | US- | | | | |
| I | US- | | | | |
| J | US- | | | | |
| K | US- | | | | |
| L | US- | | | | |
| M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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